

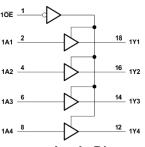
SN74AHCT244-Q1 Automotive Octal Buffer/Driver with 3-State Outputs

1 Features

- Qualified for automotive applications
- ESD protection exceeds 1000V per MIL-STD-883, method 3015
- EPIC™ (enhanced-performance implanted CMOS) process
- Inputs are TTL-voltage compatible

2 Applications

- Enable or disable a digital signal
- Eliminate slow or noisy input signals
- Hold a signal during controller reset
- Debounce a switch



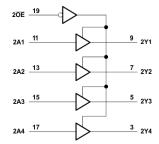
3 Description

This octal buffer/driver is designed specifically to improve both the performance and density of 3state memory-address drivers, clock drivers, and busoriented receivers and transmitters.

Package Information

PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)	BODY SIZE(3)
SN74AHCT244-Q1	DW (SOIC, 20)	12.80mm × 10.3mm	12.8mm x 7.5mm
3N/4AHC1244-Q1	PW (TSSOP, 20)	6.50mm × 6.4mm	6.50mm x 4.40mm

- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



Logic Diagram (Positive Logic)



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4 Pin Configuration and Functions

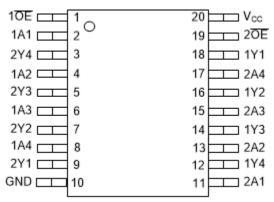


Figure 4-1. DW or PW Package (Top View)

Table 4-1. Pin Functions

PIN		1/0	DESCRIPTION
NO.	NAME	I/O	DESCRIPTION
1	1 OE	I	Output Enable 1
2	1A1	I	1A1 Input
3	2Y4	0	2Y4 Output
4	1A2	I	1A2 Input
5	2Y3	0	2Y3 Output
6	1A3	I	1A3 Input
7	2Y2	0	2Y2 Output
8	1A4	I	1A4 Input
9	2Y1	0	2Y1 Output
10	GND	_	Ground pin
11	2A1	I	2A1 Input
12	1Y4	0	1Y4 Output
13	2A2	I	2A2 Input
14	1Y3	0	1Y3 Output
15	2A3	I	2A3 Input
16	1Y2	0	1Y2 Output
17	2A4	I	2A4 Input
18	1Y1	0	1Y1 Output
19	2 OE	I	Output Enable 2
20	VCC	_	Power Pin



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
V _{CC}	Supply voltage range	-0.5	7	V
V _I ¹	Input voltage range	-0.5	7	V
V _O ¹	Output voltage range	-0.5	V _{CC} + 0.5	V
$I_{IK}(V_I < 0)$	Input clamp current		-20	mA
I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	Output clamp current		±20	mA
$I_O (V_O = 0 \text{ to } V_{CC})$	Continuous output current		±25	mA
	Continuous current through V _{CC} or GND		±75	mA
T _{stg}	Storage temperature range	-65	150	°C

⁽¹⁾ The input and output voltage ratings may be exceeded if the input and output current ratings are observed. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 ESD Ratings

			Value	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±1000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

(over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		4.5	5.5	V
V _{IH}	High-level input voltage		2		V
V _{IL}	Low-level input voltage			0.8	V
VI	Input voltage		0	5.5	V
Vo	Output voltage		0	V _{CC}	V
I _{OH}	High-level output current			-8	mA
I _{OL}	Low-level output current			8	mA
T _A	Operating free air temperature	I-suffix device	-40	85	°C
	Operating free-air temperature	Q-suffix device	-40	125	C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		SN74AHC		
		DW	UNIT	
		20 PI	NS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	58	116.8	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

Product Folder Links: SN74AHCT244-Q1

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T _A	= 25°C		MIN	MAX	UNIT
PARAMETER	TEST SONDITIONS	V _{CC}	MIN	TYP	MAX	IVIIIN	WAA	UNII
V _{OH}	I _{OH} = -50 mA	4.5 V	4.4	4.5		4.4		V
VOH	I _{OH} = -8 mA	4.5 V	3.94			3.8		v
V	I _{OL} = 50 mA			0.1		0.1	V	
V _{OL}	I _{OL} = 8 mA	4.5 V			0.36		0.44	'
I _{OZ}	V _O = V _{CC} or GND	5.5 V			±0.25		±2.5	μA
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			±0.1		±1	μA
I _{CC}	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		40	μA
ΔI _{CC} ⁽¹⁾	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35	1.5		μA
C _i	V _I = V _{CC} or GND	5 V		2.5	10			pF
Co	V _O = V _{CC} or GND	5 V		3				pF

(1) This is the increase in supply current for each input at one of the specified TTL voltage levels, rather than 0 V or V_{CC}.

5.6 Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 6-1)

DADAMETED	FROM (INDUT)	TO (OUTPUT)	LOAD	T _A = 25	°C	MAIN	MAY	LINUT
PARAMETER	FROM (INPUT)	TO (OUTPUT)	CAPACITANCE	MIN TYP	MAX	MIN	MAX	UNIT
t _{PLH}	Α	Y	C _L = 15 pF	5.4	7.4	1	8.5	ns
t _{PHL}	Α	ı	О 13 рг	5.4	7.4	1	8.5	115
t _{PZH}	ŌĒ	Y	C ₁ = 15 pF	7.7	10.4	1	12	no
t _{PZL}	OE	r	OL = 15 pr	7.7	10.4	1	12	ns
t _{PHZ}	ŌĒ	Y	C _L = 15 pF	5	9.4	1	10	ns
t _{PLZ}	OL	ı	Ο <u>Γ</u> – 13 με	5	9.4	1	10	115
t _{PLH}	Α	Y	C _L = 50 pF	5.9	8.4	1	9.5	ns
t _{PHL}	Α	ı	C _L = 30 μ	5.9	8.4	1	9.5	115
t _{PZH}	ŌĒ	Y	C _L = 50 pF	8.2	11.4	1	13	no
t _{PZL}	OE	r	C _L = 50 pr	8.2	11.4	1	13	ns
t _{PHZ}	- Y C _L = 50 pF	V	C = 50 pE	8.8	11.4	1	13	no
t _{PLZ}		O _L = 50 pr	8.8	11.4	1	13	ns	
t _{sk(o)}			C _L = 50 pF		1			ns

5.7 Noise Characteristics

 $V_{CC} = 5 \text{ V}, C_L = 50 \text{ pF}, T_A = 25^{\circ}\text{C}^{(1)}$

	PARAMETER	MIN	TYP	MAX	UNIT
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.1		V
V _{IH(D)}	High-level dynamic input voltage	2			V
$V_{IL(D)}$	Low-level dynamic input voltage			8.0	V

(1) Characteristics are for surface-mount packages only.

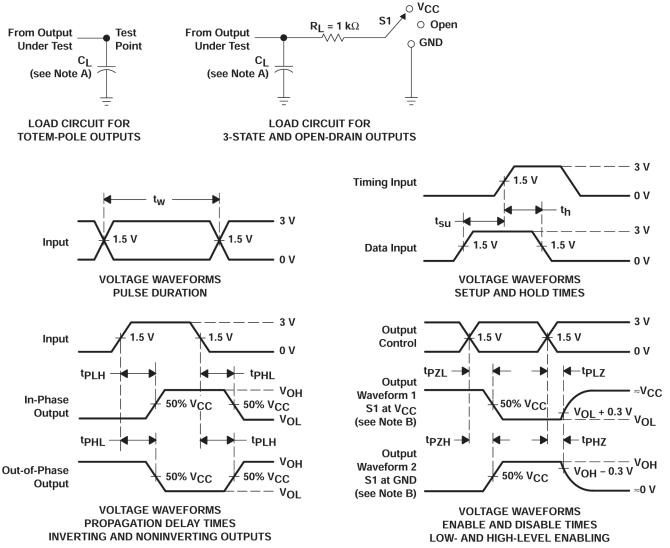
5.8 Operating Characteristics

 $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
С	Power dissipation capacitance	No load, f = 1 MHz	8.2	pF



6 Parameter Measurement Information



- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 3 ns. $t_f \leq$ 3 ns.
- D. The outputs are measured one at a time, with one input transition per measurement.

Figure 6-1. Load Circuit and Voltage Waveforms

TEST	S1
t _{PLH} /t _{PHL}	Open
t _{PLZ} /t _{PZL}	V _{CC}
t _{PHZ} /t _{PZH}	GND
Open Drain	V _{CC}

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7 Detailed Description

7.1 Overview

The SN74AHCT244 is organized as two 4-bit buffers/line drivers with separate output-enable (\overline{OE}) inputs. When \overline{OE} is low, the device passes data from the A inputs to the Y outputs. When \overline{OE} is high, the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} shall be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

7.2 Functional Block Diagram

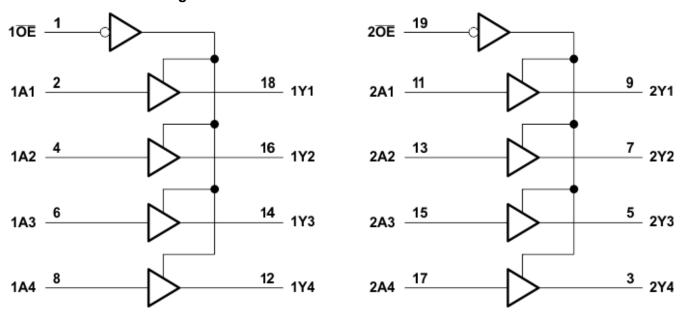


Figure 7-1. Logic Diagram (Positive Logic)

7.3 Device Functional Mode

Table 7-1. (Each 4-Bit Buffer/Driver)

INP	OUTPUT Y				
ŌĒ	Α	0017011			
L	Н	Н			
L	L	L			
Н	X	Z			

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in the Section 5.3 table.

Each VCC pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, $0.1~\mu f$ is recommended; if there are multiple VCC pins, then $0.01~\mu f$ or $0.022~\mu f$ is recommended for each power pin. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. A $0.1~\mu f$ and a $1~\mu f$ are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

8.2 Layout

8.2.1 Layout Guidelines

When using multiple-bit logic devices, inputs should never float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such input pins should not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. Section 8.2.1.1 specifies the rules that must be observed under all circumstances. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they will be tied to GND or V_{CC} , whichever makes more sense or is more convenient. It is generally acceptable to float outputs, unless the part is a transceiver. If the transceiver has an output enable pin, it will disable the output section of the part when asserted. This will not disable the input section of the I/Os, so they cannot float when disabled.

Product Folder Links: SN74AHCT244-Q1



8.2.1.1 Layout Example

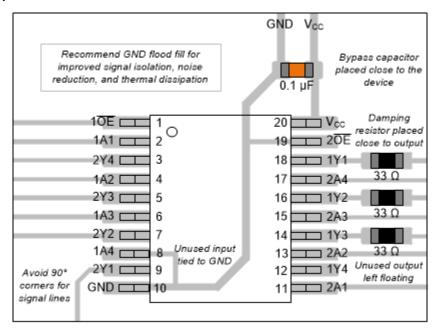


Figure 8-1. Layout Diagram



9 Device and Documentation Support

9.1 Documentation Support

9.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 9-1. Related Links

PARTS	PARTS PRODUCT FOLDER		TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY		
SN74AHCT244-Q1	Click here	Click here	Click here	Click here	Click here		

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision D (April 2023) to Revision E (August 2024)	Page
•	Deleted references to machine model throughout data sheet	1
•	Added package size to Package information table	1
	Updated RθJA values: PW = 83 to 116.8, all values in °C/W	

Changes from Revision C (April 2008) to Revision D (April 2023)

Page

 Added Applications, Package Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section.

Product Folder Links: SN74AHCT244-Q1



11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable part number	Status	Material type	Package Pins	Package qty Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
						(4)	(5)		
CAHCT244IPWRG4Q1	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I
CAHCT244IPWRG4Q1.A	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I
CAHCT244QDWRG4Q1	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
CAHCT244QDWRG4Q1.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
CAHCT244QPWRG4Q1	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
CAHCT244QPWRG4Q1.A	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
CAHCT244QWRKSRQ1	Active	Production	VQFN (RKS) 20	3000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB244Q
SN74AHCT244IPWRQ1	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I
SN74AHCT244IPWRQ1.A	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHCT244I
SN74AHCT244QDGSRQ1	Active	Production	VSSOP (DGS) 20	5000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HB244Q
SN74AHCT244QDWRQ1	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
SN74AHCT244QDWRQ1.A	Active	Production	SOIC (DW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
SN74AHCT244QPWRQ1	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q
SN74AHCT244QPWRQ1.A	Active	Production	TSSOP (PW) 20	2000 LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 125	AHCT244Q

⁽¹⁾ Status: For more details on status, see our product life cycle.

⁽²⁾ Material type: When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

⁽³⁾ RoHS values: Yes, No, RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

⁽⁴⁾ Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

⁽⁵⁾ MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

⁽⁶⁾ Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

PACKAGE OPTION ADDENDUM

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Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF SN74AHCT244-Q1:

Catalog: SN74AHCT244

Enhanced Product: SN74AHCT244-EP

Military: SN54AHCT244

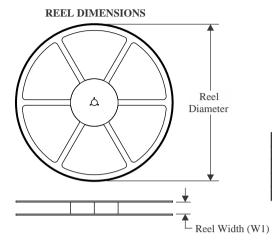
NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications



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TAPE AND REEL INFORMATION



TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
CAHCT244QDWRG4Q1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CAHCT244QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
CAHCT244QWRKSRQ1	VQFN	RKS	20	3000	180.0	12.4	2.8	4.8	1.2	4.0	12.0	Q1
SN74AHCT244IPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN74AHCT244QDGSRQ1	VSSOP	DGS	20	5000	330.0	16.4	5.4	5.4	1.45	8.0	16.0	Q1
SN74AHCT244QDWRQ1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN74AHCT244QPWRQ1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1



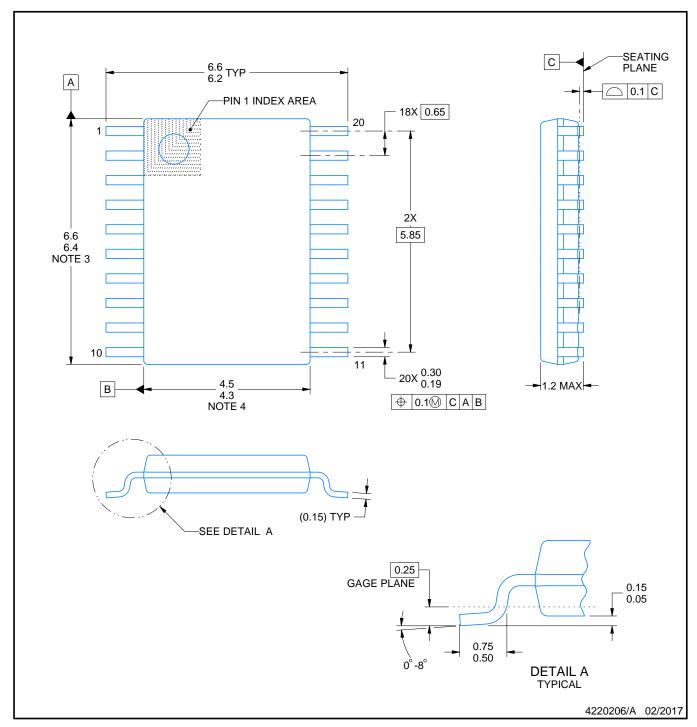
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*All dimensions are nominal

All difficultions are norminal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0
CAHCT244IPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0
CAHCT244QDWRG4Q1	SOIC	DW	20	2000	356.0	356.0	45.0
CAHCT244QPWRG4Q1	TSSOP	PW	20	2000	353.0	353.0	32.0
CAHCT244QWRKSRQ1	VQFN	RKS	20	3000	210.0	185.0	35.0
SN74AHCT244IPWRQ1	TSSOP	PW	20	2000	353.0	353.0	32.0
SN74AHCT244QDGSRQ1	VSSOP	DGS	20	5000	353.0	353.0	32.0
SN74AHCT244QDWRQ1	SOIC	DW	20	2000	356.0	356.0	45.0
SN74AHCT244QPWRQ1	TSSOP	PW	20	2000	353.0	353.0	32.0





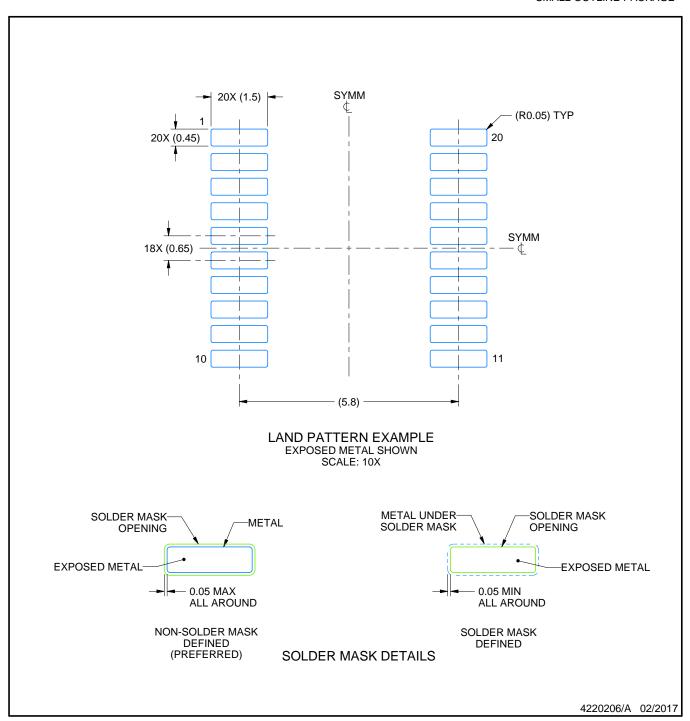
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



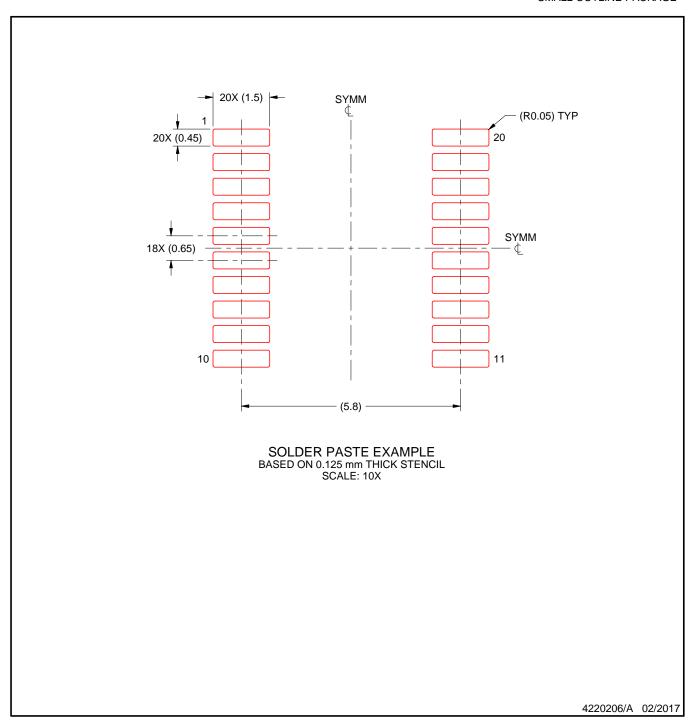


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



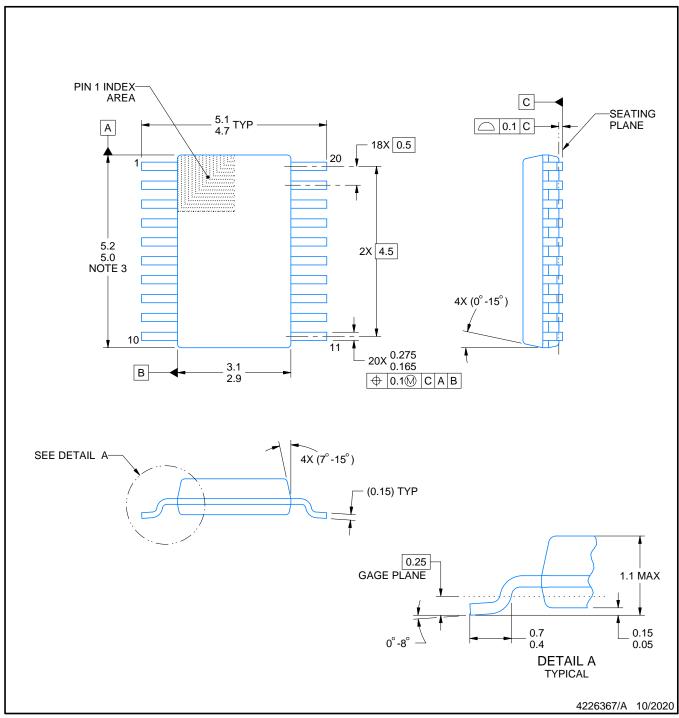


NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







NOTES:

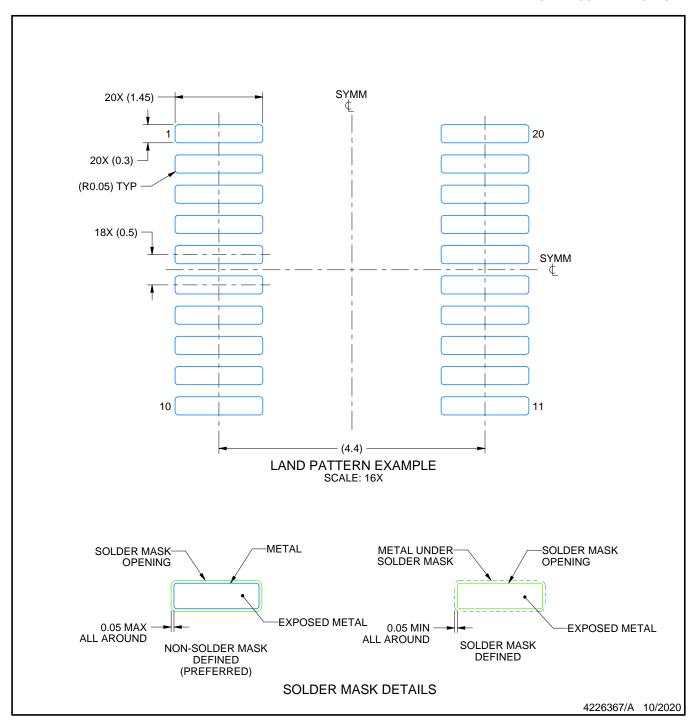
PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. No JEDEC registration as of September 2020.
- 5. Features may differ or may not be present.

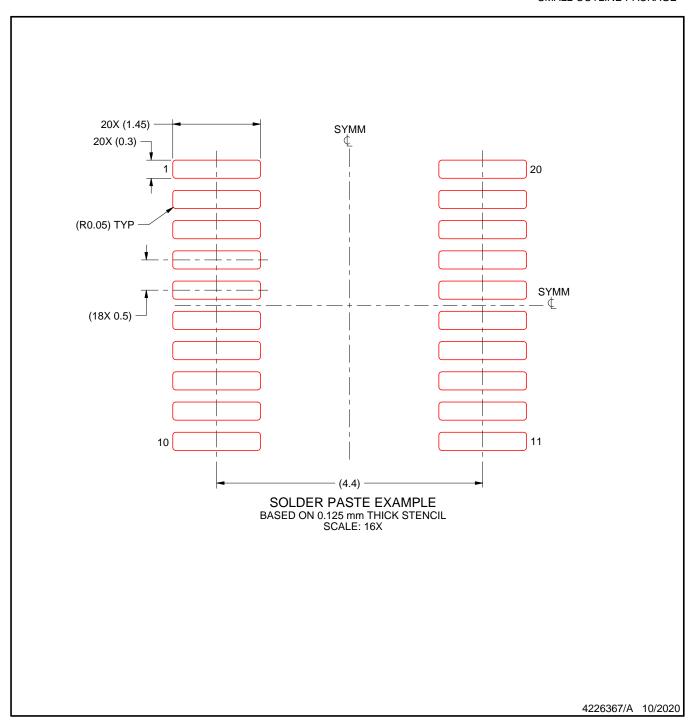




NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- 8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
- 9. Size of metal pad may vary due to creepage requirement.
- 10. Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.





NOTES: (continued)

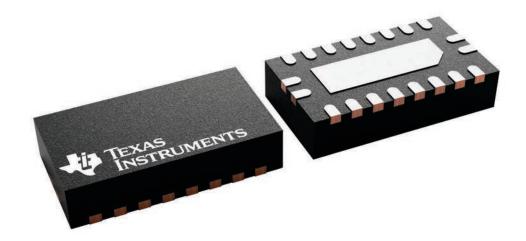
- 11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 12. Board assembly site may have different recommendations for stencil design.



2.5 x 4.5, 0.5 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



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SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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